EH2920TS-34.368M

Mechanical Shock

Moisture Resistance

Moisture Sensitivity

Solderability

Vibration

Resistance to Solvents

Temperature Cycling

Resistance to Soldering Heat



EH29 20

Series -RoHS Compliant (Pb-free) 1.8V 4 Pad 5mm x 7mm Ceramic SMD LVCMOS Oscillator

Frequency Tolerance/Stability ±20ppm Maximum

TS -34.368M - Nominal Frequency

34.368MHz

Pin 1 Connection Tri-State (High Impedance)

Operating Temperature Range -0°C to +70°C

Duty Cycle 50 ±10(%)

ELECTRICAL SPECIFICATIONS		
Nominal Frequency	34.368MHz	
Frequency Tolerance/Stability	±20ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°, 260°C Reflow, Shock, and Vibration)	
Aging at 25°C	±5ppm/Year Maximum	
Operating Temperature Range	0°C to +70°C	
Supply Voltage	1.8Vdc ±5%	
Input Current	4mA Maximum (No Load)	
Output Voltage Logic High (Voh)	90% of Vdd Minimum (IOH = -8mA)	
Output Voltage Logic Low (Vol)	10% of Vdd Maximum (IOL = +8mA)	
Rise/Fall Time	6nSec Maximum (Measured at 20% to 80% of waveform)	
Duty Cycle	50 ±10(%) (Measured at 50% of waveform)	
Load Drive Capability	15pF Maximum	
Output Logic Type	CMOS	
Pin 1 Connection	Tri-State (High Impedance)	
Tri-State Input Voltage (Vih and Vil)	90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance)	
Standby Current	10μA Maximum (Pin 1 = Ground)	
Absolute Clock Jitter	±100pSec Maximum	
Start Up Time	10mSec Maximum	
Storage Temperature Range	-55°C to +125°C	
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500V	
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	
Flammability	UL94-V0	
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	

MIL-STD-883, Method 2002, Condition B

MIL-STD-202, Method 210, Condition K

MIL-STD-883, Method 1010, Condition B

MIL-STD-883, Method 2007, Condition A

MIL-STD-883, Method 1004

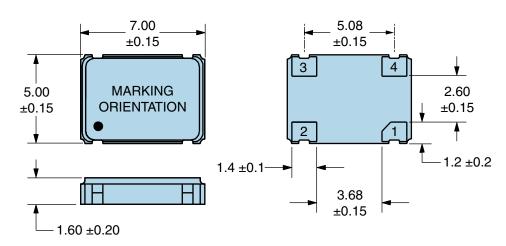
MIL-STD-202, Method 215

MIL-STD-883, Method 2003

J-STD-020, MSL 1

EH2920TS-34.368M

MECHANICAL DIMENSIONS (all dimensions in millimeters)



PIN	CONNECTION	
1	Tri-State	
2	Case Ground	
3	Output	
4	Supply Voltage	
	MARKING	
LINE	MARKING	
LINE 1	MARKING ECLIPTEK	

Suggested Solder Pad Layout

All Dimensions in Millimeters



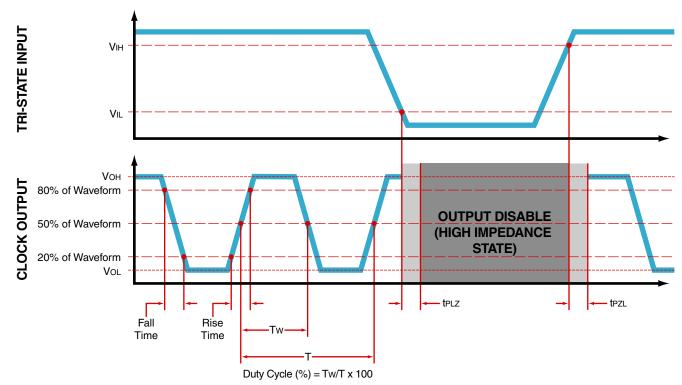
All Tolerances are ±0.1



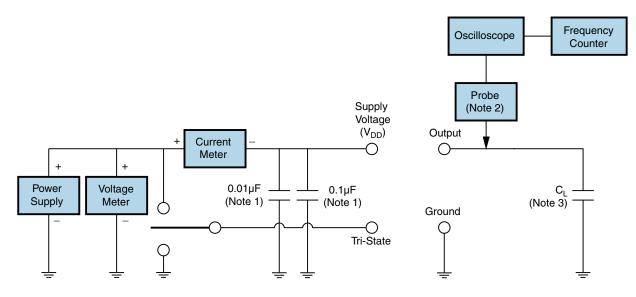
EH2920TS-34.368M



OUTPUT WAVEFORM & TIMING DIAGRAM



Test Circuit for CMOS Output

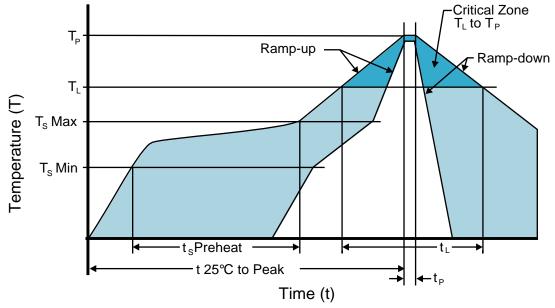


- Note 1: An external 0.01µF ceramic bypass capacitor in parallel with a 0.1µF high frequency ceramic bypass capacitor close (less than 2mm) to the package ground and supply voltage pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

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Recommended Solder Reflow Methods



High Temperature Infrared/Convection

EH2920TS-34.368M

<u> </u>	
T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	150°C
- Temperature Typical (T _s TYP)	175°C
 Temperature Maximum (T_s MAX) 	200°C
- Time (t _s MIN)	60 - 180 Seconds
Ramp-up Rate (T⊾ to T _P)	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T _P Target)	250°C +0/-5°C
Time within 5°C of actual peak (t _p)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

ECLIPTEK CORPORATION

Recommended Solder Reflow Methods

EH2920TS-34.368M



Low Temperature Infrared/Convection 240°C

T_s MAX to T_L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	N/A
 Temperature Typical (T_s TYP) 	150°C
 Temperature Maximum (T_s MAX) 	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T _L to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	240°C Maximum
Target Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (t _p)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to body of device.

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)